

## 12500 TI Boulevard, MS 8640, Dallas, Texas 75243

# PCN# 20180918001 Qualify 0.8mil Cu wire diameter for select devices Change Notification / Sample Request

**Date:** September 20, 2018 **To:** Newark/Farnell PCN

#### Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The proposed first ship date is indicated on page 3 of this notification, unless customer agreement has been reached on an earlier implementation of the change.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (PCN www admin team@list.ti.com).

Sincerely,

PCN Team SC Business Services

## 20180918001 Attachment: 1

## **Products Affected:**

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

**DEVICE** LMV358AIDR TLV9002IDR TSV912AIDR **CUSTOMER PART NUMBER** 

null null null

Technical details of this Product Change follow on the next page(s).

PCN Number:			20180918001 <b>PCN Date:</b> Sept						Sept 20, 2	2018				
Title: Qualify 0.8mi		I Cu wire diameter for select devices												
<b>Customer Contact:</b>			t:	PC	PCN Manager Dept: Quality Serv				rices					
Proposed 1 <sup>st</sup> Ship Date			Date	- 1 1)47: 711 711 8 1				Date Provided at Sample request						
Chan	ige T	уре:		•						•				
	Assei	mbly Site		Des			De	sign	gn			Wafer Bump Site		
		mbly Prod					Data Sheet			Wafer Bump Material				
		mbly Mat						Part number change			Wafer Bump Process			
		anical Sp		ation				Test Site			Wafer Fab Site			
	Packi	ng/Shipp	ing/L	abe	eling		Tes	Test Process			Wafer Fab Materials			
											Wafer Fab	Process		
	PCN Details													
Desc	ripti	on of Ch	ange:											
Texas Instruments Incorporated is announcing the qualification of 0.8mil Cu wire diameter for select devices listed in the "Product Affected" Section.  Wire Diameter:														
				Current			Proposed							
Wi	Wire Diameter		1.	1.0mil Cu wire				0.8mil Cu wire						
Reason for Change:														
Continuity of supply.														
Antic	cipat	ed impa	ct on	Fo	rm, Fit	, Fun	ctic	on, Quality	or Relial	oilit	y (positive /	negative)	:	
None														
Anticipated impact on Material Declaration														
No Impact to the Material Declaration			Material Declarations or Product Content reports are driven from production data and will be available following the production release. Upon production release the revised reports can be obtained from the TI Eco-Info website. There is no impact to the material meeting current regulatory compliance requirements with this PCN change.											
Changes to product identification resulting from this PCN:														
None														
Product Affected:														
LM358LVIDR				MCP6292IDR			SN1711	L004DR		TLV9062ID	R			
LMV358AIDR				SN1605025DR			TLV900			TSV912AID				
	SINIOUSUZSEIN TENSUOZIEN TSVSTZAIEN													

# **Qualification Report**

# TLV9062IDR - New Capillary & Wire Diam

Approve Date 04-Sep-2018

## **Product Attributes**

Attributes	Qual Device: <u>TLV9062ID</u>	QBS Product Reference: <u>TLV9062ID</u>	QBS Process Reference: <u>TLV9002ID</u>
Assembly Site	AMK P1	AP1	AP1
Package Family	SOIC	SOIC	SOIC
Flammability Rating	UL 94 V-0	UL 94 V-0	UL 94 V-0
Wafer Fab Supplier	RFAB	RFAB	RFAB
Wafer Process	LBC9	LBC9	LBC9

<sup>-</sup> QBS: Qual By Similarity

## **Qualification Results**

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: <u>TLV9062ID</u>	QBS Product Reference: <u>TLV9062ID</u>	QBS Process Reference: <u>TLV9002ID</u>	
ED	Electrical Characterization	Per Datasheet Parameters	-	Pass	Pass	
ELFR	Early Life Failure Rate, 125C	48 Hours	-	3/2400/0	-	
HAST	Biased HAST, 130C/85%RH	96 Hours	-	3/231/0	1/77/0	
HBM	ESD - HBM	4000 V	-	3/18/0	-	
CDM	ESD - CDM	1500 V	-	3/9/0	1/3/0	
HTOL	Life Test, 150C	300 Hours	-	3/231/0	1/77/0	
HTSL	High Temp. Storage Bake, 170C	420 Hours	3/231/0	3/231/0	1/77/0	
LU	Latch-up	(per JESD78)	-	3/18/0	1/6/0	
SD	Solderability	Pb Free	-	3/66/0	-	
TC	Temperature Cycle, - 65/150C	500 Cycles	3/231/0	3/231/0	1/77/0	
UHAST	Unbiased HAST, 130C/85%RH	96 Hours	3/231/0	3/231/0	1/77/0	

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at Tl's external Web site: http://www.ti.com/

### Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

THIS INFORMATION RELATING TO QUALITY AND RELIABILITY IS PROVIDED "AS IS." Product information detailed in this report may not accurately reflect TI's current product materials, processes and testing used in the construction of the TI products. Customers are solely responsible to conduct sufficient engineering and additional qualification testing to determine whether a device is suitable for use in their applications. Using TI products outside limits stated in TI's datasheet may void TI's warranty. See TI's Terms of Sale at <a href="http://www.ti.com/lsds/ti/legal/termsofsale.page">http://www.ti.com/lsds/ti/legal/termsofsale.page</a>

<sup>-</sup> Qual Device TLV9062ID is qualified at LEVEL2-260C

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com